CLASSIFICATION WITH CLASS-INDEPENDENT QUALITY INFORMATION FOR BIOMETRIC VERIFICATION

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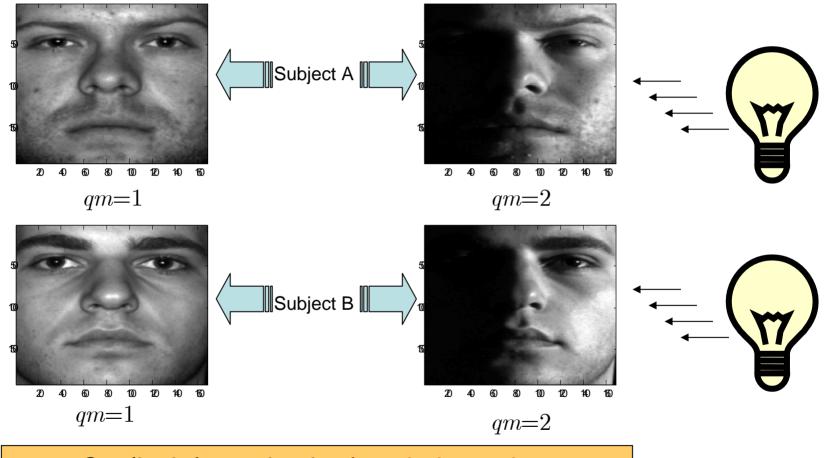
- What is class-independent quality information in biometrics?
- How can class-independent information help in pattern classification?
- How to systematically improve biometric verification with quality information?
- Conclusions





Quality measures in biometrics

Images from the Extended Yale B corpus



Quality information is class-independent





Motivation of this work

- Biometric data is **rarely** of constant, controlled quality
- Inconsistent data quality \Rightarrow classification **ERRORS**
- Current understanding of the role of quality measures is more intuitive than systematic
- Existing approaches are mostly heuristic and ad-hoc

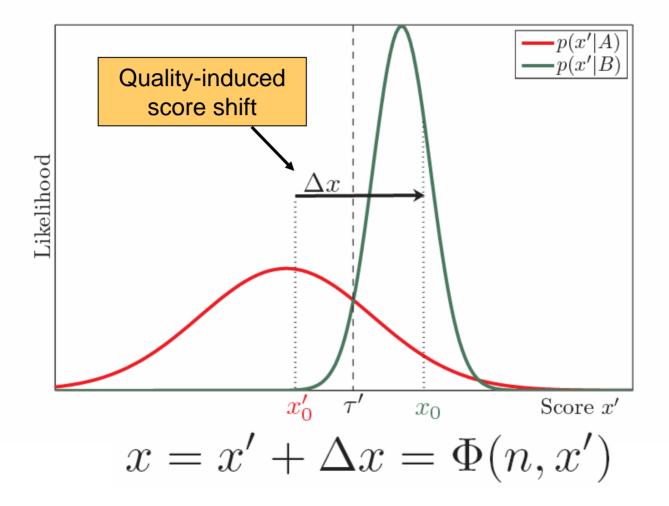
OBJECTIVE

Create a **systematic method** of classification with **quality measures**, **generalizable** to single-, multiclassifier and multimodal systems.





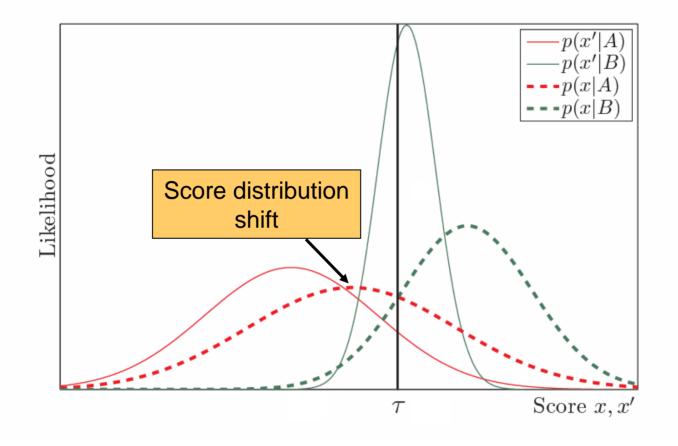
Why errors occur?







Why errors occur?



Distribution/model shift observed in face, fingerprint, speaker verification etc.





Why errors occur?

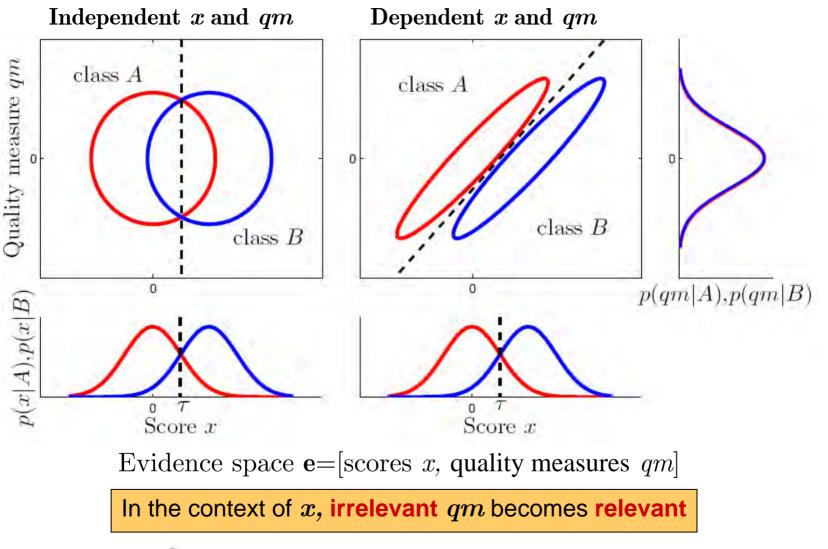
Shift in score distributions $\downarrow \downarrow$ Scores *x* and signal quality are **DEPENDENT** $\downarrow \downarrow$ **Scores** *x* and **quality measures** *qm* are **DEPENDENT**





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Improving classification with class-independent information







Properly collected quality measures are relevant, class-independent classification features.

Stronger dependence between quality measures and baseline classifier scores can lead to better class separation.

Class-independent quality features can help improve classification.





- Scores and quality measures can be considered as classification features
- Stronger dependence between quality measures and baseline classifier scores can lead to improved class separation
- Actual dependencies are hard to model analytically
- Data-driven approach: dependencies learned from data

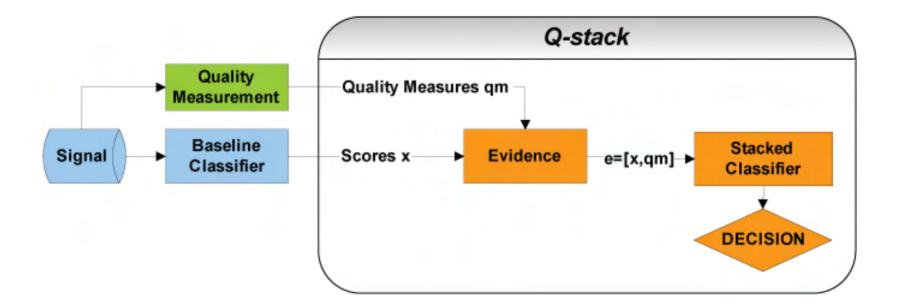
Q-stack: a generalized stacking-based framework of classification using quality measures





How to use quality measures?

- Introducing **Q-stack**
- Based on the concept of *classifier stacking*

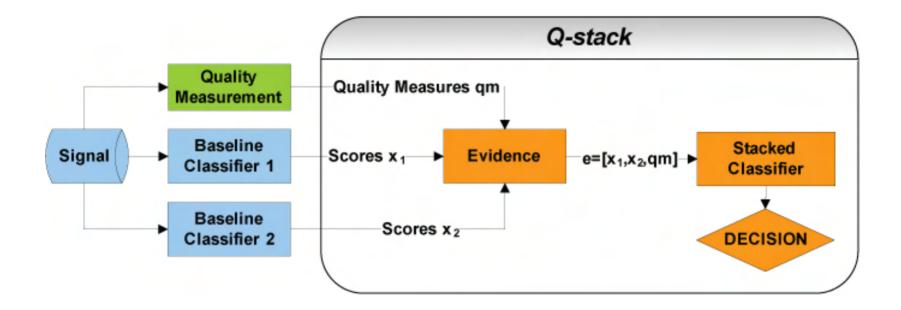






How to use quality measures?

Q-stack: multiple classifier application

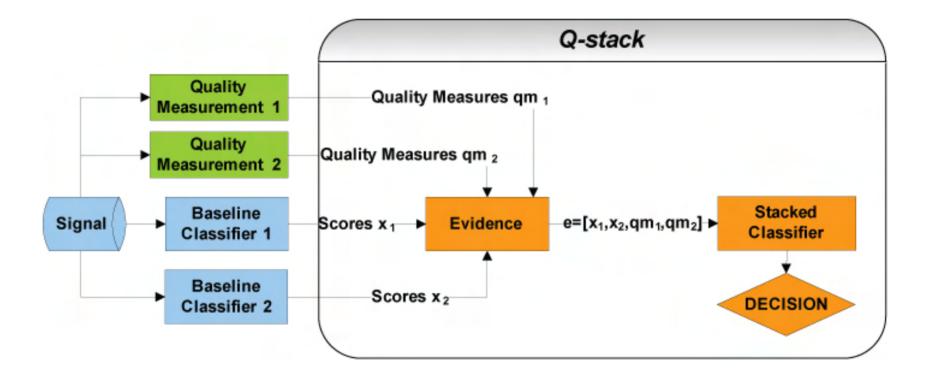






How to use quality measures?

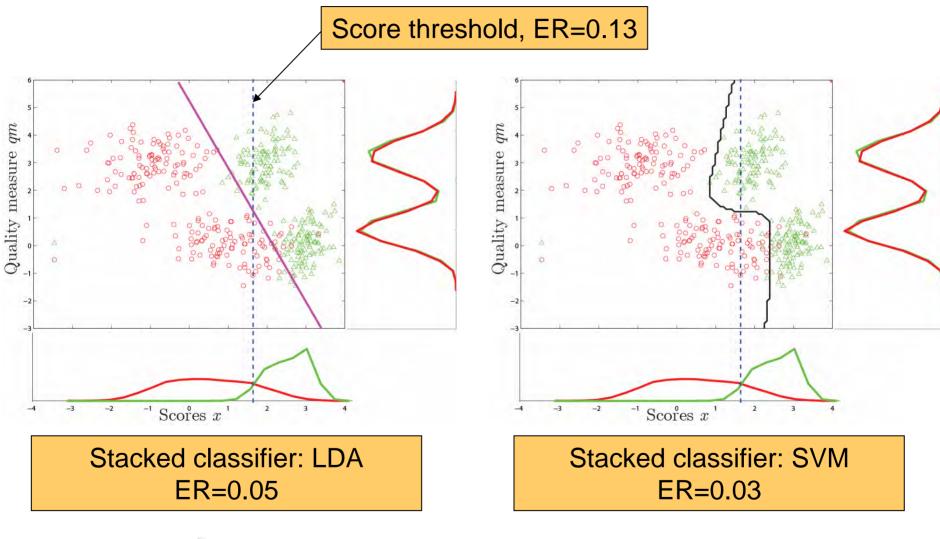
Q-stack: multiple quality measures







Q-stack: synthetic example







Q-stack as a generalized framework

- Seeks an optimal decision boundary in the evidence space
- One stacked classifier
- Modality-independent
- Accepts multiple quality measures
- Generalizable to existing approaches

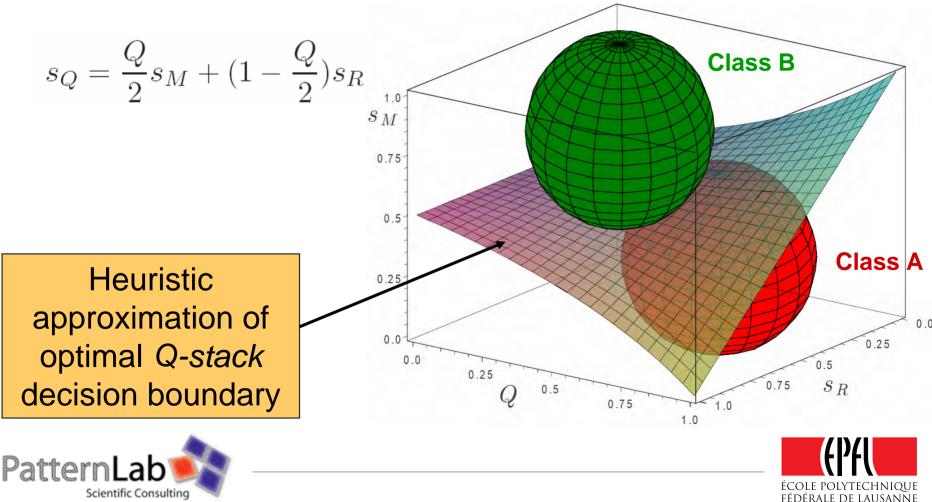




Generalization example – multiple classifier systems

Fusion function with quality parameter

Example of a multi-classifier fusion function



Goal of the experiment: To demonstrate that quality measures bring a systematic improvement over baseline systems.

Used modalities: face, fingerprint

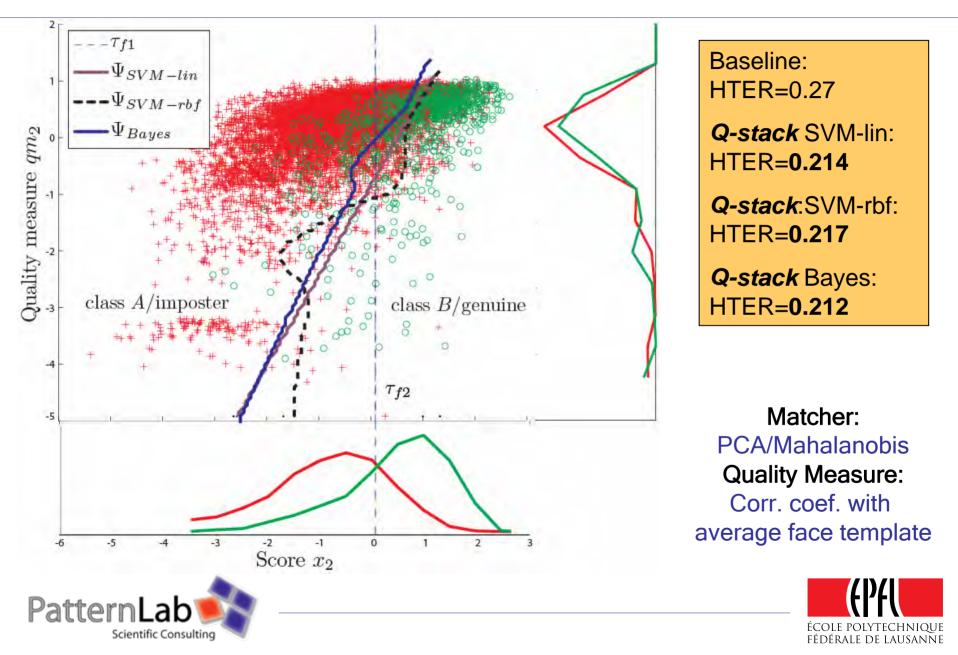
Used stacked classifiers in the Q-stack framework:



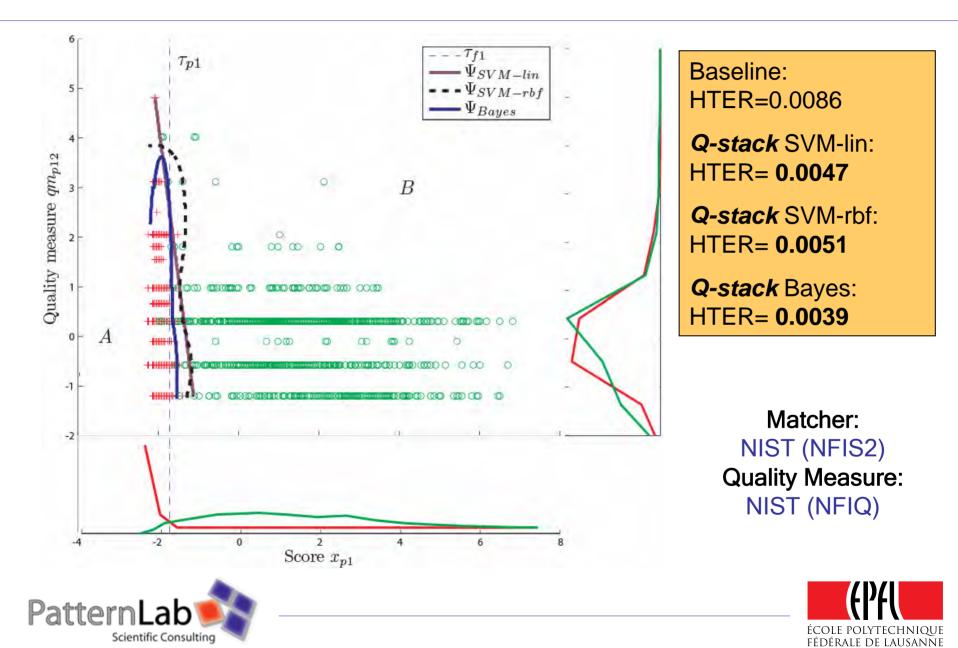




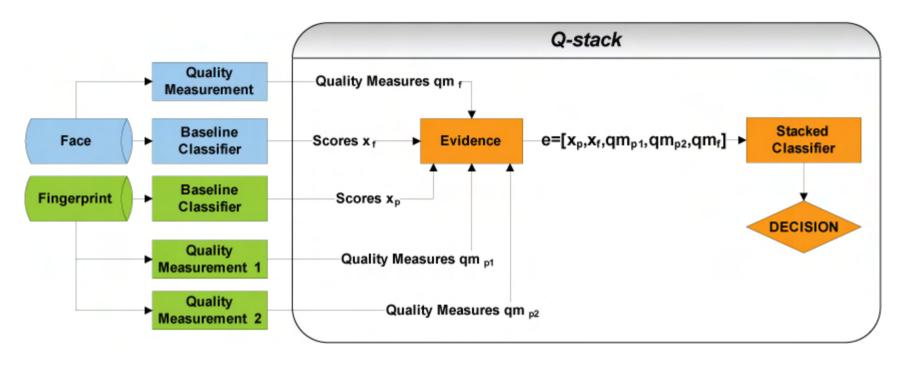
Experimental evaluation: face verification



Experimental evaluation: fingerprint verification



Experimental evaluation: multimodal fusion



Baseline fusion				
	HTER	ER _A	ER _B	
SVM-lin	0.0076	0.0033	0.0118	
Bayes	0.0056	0.001	0.0013	

Q-stack				
	HTER	ER _A	ER _B	
SVM-lin	0.0026	0.0029	0.0022	
Bayes	0.0027	0.0038	0.0017	





Conclusions

- Quality measures can be treated as classification features
- Class-independent quality measures can help separate between classes, given their dependence on the baseline classifier scores
- Proposed method Q-stack is a general framework of classification with quality measures in
 - single classifier systems
 - multi-classifier/multimodal systems
- Theoretical findings are supported by experiments with real biometric data





• Parts of presented results can be found in:

Quality measures in unimodal and multimodal biometric verification, J. Richiardi, K. Kryszczuk, A. Drygajlo, 15th European Conference on Signal Processing EUSIPCO 2007, Poznan, Poland.

Improving classification with class-independent quality measures: Q – stack in face verification, K. Kryszczuk, A. Drygajlo, 2nd International Conference in Biometrics ICB2007, Seoul Korea, August 2007

Q – stack: uni- and multimodal classifier stacking with quality measures, K. Kryszczuk, A. Drygajlo, 7th International Workshop on Multiple Classifier Systems 2007, Prague, Czech Republic



